

Abstract of the Disclosure

Image analysis techniques may be provided. Location of objects in an image may be determined based on intensity characteristics of pixels in the image.

5 Objects that have been located may be mapped to a source for the objects based for example, on a grid structure that may have been used to place the objects. Differential analysis of objects of two source materials in images may be determined based on aligned

10 versions of the images. Filtering may be used to weigh pixel characteristics. Such object analysis techniques may have been encoded into a set of machine-executable instructions and stored on a machine-readable storage medium for use by equipment that is to perform the

15 techniques.